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09/753607



	Class Subclass	ISSUE CLASSIFICATION

U.S. UTILITY Patent Application

012	O.I.P.E.	PATENT DATE
AKM	Gu 3	4/11
SCANNED	Q.A.	

APPLICATION NO. 09/753607	CONT/PRIOR F	CLASS 549	SUBCLASS 765	ART UNIT 2829	EXAMINER NGUYEN, VINH
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324

TITLE

Array substrate and method of inspecting the same

PTO-2040
12/99

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
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	(Primary Examiner)	(Date)		Amount Due	Date Paid
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